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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/655,689	09/05/2003	Yian-Liang Kuo	TS03-337	6492	
24504	7590 02/28/2006		EXAMINER		
THOMAS, KAYDEN, HORSTEMEYER & RISLEY, LLP			NGUYEN, DILINH P		
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Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
	10/655,689	KUO ET AL.			
Office Action Summary	Examiner	Art Unit			
	DiLinh Nguyen	2814			
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).					
Status					
 1) Responsive to communication(s) filed on <u>02 Description</u> 2a) This action is FINAL. 2b) This 3) Since this application is in condition for alloware closed in accordance with the practice under Expression. 	action is non-final. nce except for formal matters, pro				
Disposition of Claims					
4) ☐ Claim(s) 38-52 and 55-57 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 38-52,55-57 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or election requirement.					
Application Papers					
9) The specification is objected to by the Examiner. 10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner. Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.					
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s)					
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:				

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

2. Claims 38, 49-50 and 57 are rejected under 35 U.S.C. 102(b) as being anticipated by Shishido et al. (U.S. Pat. 6,294,831) (previously applied).

Shishido et al. disclose an ball grid array package, comprising:

a semiconductor chip/die 14 affixed to a ball grid substrate 12; the ball grid substrate having a series of balls 24; and

a heat spreader mounted to the semiconductor chip/die and the ball grid substrate opposite the series of balls; the heat spreader having a pattern of slots 48, not completely piercing the heat spreader, therein, wherein the pattern of the slots comprises a pattern selected from the group consisting of: a circular pattern, a radiating pattern, rectangular pattern or various combinations thereof (cover fig., column 4, lines 53-58).

- Regarding claim 49, Shishido et al. disclose the slots penetrate the heat spreader from about 25 to 85 % (cover fig., fig. 4b or 5b).
- Regarding claim 50, Shishido et al. disclose that the slots penetrate the heat spreader from about 50 to 75% (cover fig., fig. 4b or 5b).

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 Regarding claim 57, Shishido et al. disclose an ball grid array package, comprising:

a semiconductor chip/die 14 affixed to a ball grid substrate 12, the ball grid substrate having a series of balls 24; and

a heat spreader mounted to the semiconductor chip/die and the ball grid substrate opposite the series of balls; the heat spreader having a pattern of slots 48, not completely piercing the heat spreader, therein, wherein the slots penetrate the heat spreader from about 50 to 75% (cover fig., 4b or 5b, column 4, lines 40-50).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 39-40 and 45-46 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shishido (U.S. Pat. 6294831) (previously applied) in view of Ho et al. (U.S. Pat. 2002/0079570) (previously applied).
 - Regarding claims 39-40, Shishido substantially discloses all the limitations as claimed above except for the semiconductor chip is a silicon semiconductor chip.
 However, Ho et al. disclose a silicon semiconductor chip (paragraph 0006, line
- 4). Therefore, it would have been obvious to one having ordinary skill in the art at the

time the invention was made to replace the chip of Shishido et al. by a silicon semiconductor chip because as taught by Ho et al., such the silicon semiconductor chip is well known in the art for improving the heat dissipating characteristics (paragraph 0006).

- Regarding claims 45-46, Ho et al. disclose that the silicon semiconductor chip
 has a CTE approximately 3 ppm/°C and the heat spreader has a CTE of 18
 ppm/°C (paragraph 0006).
- 5. Claims 41-43 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shishido et al. (U.S. Pat. 6294831) (previously applied) in view of Kubo et al. (U.S. Pat. 6,199,273) (previously applied).
 - Regarding claims 41-43, Shishido et al. substantially discloses all the limitations
 as claimed above. Shishido et al. also discloses that the heat spreader 18 is
 comprised of copper (fig. 1, column 3, lines 35-46).

Shishido et al. fail to disclose the balls are comprised of 63Sn37Pb, 96.5Sn3.5Ag, 5.5Sn3.8Ag0.7Cu or 96.2Sn2.5Ag0.8Cu0.5Sb.

However, Kubo et al. discloses that a solder ball is comprised of 63Sn37Pb (column 13, lines 36-37). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Shishido et al. by having the balls are comprised of 63Sn37Pb because as taught by Kubo et al, such the 63Sn37Pb solder ball would improve the electric contact characteristic for the semiconductor package (column 13, lines 36-40).

 Regarding claim 44, Kubo et al. disclose that the balls are comprised of 96.5Sn3.5Ag (column 14, lines 28-30).

6. Claims 47-48 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shishido et al. (U.S. Pat. 6294831) (previously applied) in view of Ho et al. (U.S. Pat. 2002/0079570) (previously applied) and further in view of Jayaraman et al. (U.S. Pat. 6,724,091) (previously applied).

As discussed in details above the combination of Shishido and Ho et al. substantially disclose all the limitations as claimed above except for the chip is a germanium semiconductor chip and has a CTE of from about 5.5 to 6.5 or about 6.1.

However, Jayaraman et al. disclose that the semiconductor chip is a germanium semiconductor chip and has a CTE of about 6 ppm/° (column 1, lines 39-41). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to substitute the chip of the above combination by having a germanium semiconductor chip because as taught by Jayaraman et al., in order to use the semiconductor package in a particular application.

- 7. Claims 49-56 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shishido et al. (U.S. Pat. 6562662) (previously applied) in view of Dordi (U.S. Pat. 5835355) (previously applied).
 - Regarding claim 51, Shishido et al. do not explicitly disclose the pattern of slots include rows spaced apart from about 1.0 to 5.0 mm; the slots comprising each row are spaced apart from each other from about 0.5 to 2.5 mm.

However, Dordi (fig. 5) discloses a semiconductor package comprising a pattern of slots include rows spaced apart form about 1.0 to 5.0 mm (1.27mm or 5.08 mm, column 6, lines 10-15); the slots comprising each row are spaced apart from each other form about 0.5 to 2.5 mm (0.51mm or 1.27mm, fig. 4, column 6, lines 10-15).

Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device structure of Shishido et al. by having the pattern of slots include rows spaced apart from about 1.0 to 5.0 mm; the slots comprising each row are spaced apart from each other from about 0.5 to 2.5 mm because as taught by Dordi, in order to reduce the amount of moisture from being trapped by the heat spreader and provide good heat dissipation for the semiconductor package (fig. 5, column 3, lines 27-29).

- Regarding claim 49, Dordi discloses that the slots penetrate the heat spreader from about 25 to 85% (fig. 4).
- Regarding claim 50, Dordi discloses that the slots penetrate the heat spreader from about 50 to 75% (fig. 4).
- Regarding claim 52, Dordi discloses that the pattern of slots includes rows spaced apart form about 1.5 to 2.5 mm (fig. 4, column 6, lines 10-15); the slots comprising each row are spaced apart from each other from about 0.7 to 1.5 mm (fig. 4, column 6, lines 10-15).
- Regarding claim 53, Dordi discloses that the pattern of slots 40 are arranged in:
 perpendicular/perpendicular rows; a square pattern (fig. 4).

 Regarding claim 54, Dordi discloses that the pattern of slots 40 are arranged in parallel/perpendicular rows (fig. 4).

 Regarding claims 55-56, Dordi discloses that the ball grid array package is a super ball grid array package (fig. 5).

Response to Arguments

Applicant's arguments filed 12/2/05 have been fully considered but they are not persuasive.

 The applicant argues that Shishido et al. fail to disclose wherein the pattern of the slots comprises a circular pattern, a radiating pattern a rectangular pattern, a concentric circular pattern, or a concentric octagonal pattern.

Applicant's arguments have been fully considered but they are not persuasive because Shishido et al. clearly disclose that the heat spreader having a pattern of slots 48, not completely piercing the heat spreader, therein, wherein the pattern of the slots comprises a pattern selected from the group consisting of: a circular pattern (round configuration as shown in cover fig.), a radiating pattern (the openings penetrating the heat spreader), rectangular pattern or various combinations thereof (cover fig., column 4, lines 53-58).

• The applicant argues that the cover fig. and fig. 5a of Shishido et al. show the openings penetrating the heat spreader 46 less than 50%.

The arguments have been fully considered but they are not persuasive because the cover fig., fig. 4b or 5b of Shishido et al. clearly show the openings 44 penetrating the heat spreader 46 more than 50%.

• In response to applicant's argument that there is no suggestion to combine the references, the examiner recognizes that obviousness can only be established by combining or modifying the teachings of the prior art to produce the claimed invention where there is some teaching, suggestion, or motivation to do so found either in the references themselves or in the knowledge generally available to one of ordinary skill in the art. See *In re Fine*, 837 F.2d 1071, 5 USPQ2d 1596 (Fed. Cir. 1988)and *In re Jones*, 958 F.2d 347, 21 USPQ2d 1941 (Fed. Cir. 1992). In this case:

Shishido substantially discloses all the limitations as claimed above except for the semiconductor chip is a silicon semiconductor chip.

However, Ho et al. disclose a silicon semiconductor chip (paragraph 0006, line 4). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to replace the chip of Shishido et al. by a silicon semiconductor chip, as taught by Ho et al., such the silicon semiconductor chip is well known in the art for improving the heat dissipating characteristics (paragraph 0006).

• In response to applicant's argument that there is no motivation to combine the references, the test for obviousness is not whether the features of a secondary reference may be bodily incorporated into the structure of the primary reference; nor is it that the claimed invention must be expressly suggested in any one or all of the references. Rather, the test is what the combined teachings of the references would have suggested to those of ordinary skill in the art. See *In re Keller*, 642 F.2d 413, 208 USPQ 871 (CCPA 1981).

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Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to DiLinh Nguyen whose telephone number is (571) 272-1712. The examiner can normally be reached on 8:00AM - 6:00PM (M-F).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

DLN

PHAT X. CAO PRIMARY EXAMINER

Carmanhol